

FREE TWO-DAY WORKSHOP



Beyond the Surface: A Nanoscale Characterization and Metrology Workshop

A free workshop co-hosted by The Pennsylvania State University with Bruker
August 26-27, 2026 | 9:00 AM - 4:00 PM EDT

Explore New Advances and Research Trends

Bruker, in collaboration with The Pennsylvania State University, is pleased to invite you to a free two-day workshop on **Nanoscale Surface Characterization and Metrology**, taking place on **August 26–27, 2026**, at Penn State University.

This workshop will explore the latest advances in nanoscale characterization techniques, including [AFM](#), [AFM-IR](#), [Optical Profilometry](#), [Ellipsometry](#), and [Nanoindentation](#). Through expert presentations and live demonstrations, you will gain practical insights into nanoscale property analysis, high-speed and high-throughput measurements, and automated workflows.

You will also have the opportunity to interact directly with Bruker specialists and discuss your own measurement challenges.

Attendance is **free of charge**, but spaces are limited. Please register early to secure your spot.

We look forward to welcoming you to Penn State!

Workshop Organizers

David Louis Fecko

Director of MRI Industry Collaborations
Penn State Materials Research Institute
dlf5023@psu.edu

Timothy Tighe, Ph.D.

Metrology Lab Manager
Materials Characterization Lab
tbt1@psu.edu

Nishant Kodan

Technical Account Manager, Bruker
Nishant.Kodan@bruker.com

Jianjun Yao

Sales Account Manager for Mid
Atlantic, Bruker
Jianjun.Yao@bruker.com

Workshop Location

The Pennsylvania State University

[Millennium Science Complex](#)
Room N310
491 Pollock Road
University Park, PA 16802



Register now to secure your spot! Scan the QR code or [click here](#) to register.



Dimension Icon AFM



ContourX-500 Optical Profilometer

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Agenda — Wednesday, August 26

9:00 AM	Registration
9:20 AM	Introduction
9:30 AM	Nanoscale electrical/magnetic/mechanical/chemical characterization with AFM/AFM-IR John Thornton, Senior Applications Scientist, Bruker
10:30 AM	Optimize your Josephson junctions with magnetic field – the quick way (virtual presentation) Roeland Huijink, Senior System Engineer, Bruker
11:10 AM	Recent progress on high-speed AFM and high-throughput mechanical property measurement Jianjun Yao, Sales Account Manager of Mid Atlantic, Bruker
12:00 PM	Lunch (provided by Bruker)
1:00 PM	Automated multi-angle reflectometry and ellipsometry with the FilmTek 2000 PAR-SE Lawrence Rooney, Senior Applications Scientist, Bruker
2:00 PM	Automated non-contact 3D optical profilometry for nanofabrication Process Control Nishant Kodan, Technical Account Manager, Bruker
3:00 PM	Bridging process steps in nanofabrication: The role of Bruker TriboLab CMP Dr. Sai Krishna Kancharla, Tribology Applications Scientist
3:30 PM	Live demo on optical profilometer
4:00 PM	End of Day 1

Agenda — Thursday, August 27

9:00 AM	Hands-on sessions with AFM and optical profilometer
4:00 PM	End of Event

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